

# Isolated Single Channel Gate Driver Evaluation Board User's Manual

# NCP51152 EVBUM

### Introduction

This user guide supports the evaluation board for the NCP51152. It should be used in conjunction with the NCP51152 datasheets as well as **onsemi**'s application notes and technical support team. Please visit **onsemi**'s website at <a href="https://www.onsemi.com">www.onsemi.com</a>.

This document describes the proposed solution for an isolated single channel gate driver using the NCP51152 family. This user's guide also includes information regarding operating procedures, input/output connections, an electrical schematic, printed circuit board (PCB) layout, and a bill of material (BOM) for the evaluation board.

These evaluation boards can be used to evaluate:

- NCP51152xyDR2G
- NCV51152xyDR2G

### Description

The NCP51152 is a family of isolated single–channel gate driver with 4.5 A / 9 A source and sink peak current respectively. They are designed for fast switching to drive power MOSFETs, and SiC MOSFET power switches. The NCP51152 offers short and matched propagation delays. The NCP51152xA provides a split output that controls the rise and fall times individually. The NCP51152xB has its  $V_{CC}$  UVLO referenced to GND2 to get a true UVLO.

The NCP51152 is available in a 4 mm SOIC-8 package and can support isolation voltage up to 3.75  $kV_{RMS}.\,$ 

The NCP51152 offers other important protection function such as independent under-voltage lockout for both-side driver.

# **Key Features**

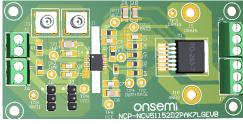
- Feature Options
  - Separated Outputs (OUTH, and OUTL) for only Variant A
  - ◆ Wide Bias Voltage Range including Negative V<sub>EE</sub> and V<sub>CC</sub> UVLO Referenced to GND2 for only Variant B
- 3 V to 20 V Input Supply Voltage
- Output Supply Voltage from 6.5 V to 30 V with 6 V and 8 V for MOSFET, 12 V and 17 V for SiC, Threshold.
- 4.5 A Peak Source, 9 A Peak Sink Output Current Capability
- Minimum CMTI of 200 V/ns dV/dt
- Propagation Delay Typical 36 ns with
  - ◆ 5 ns Max Delay Matching
- Gate Clamping during Short Circuit
- Available Package Footprint
  - ◆ Type-A: TO-3P, TO-247, D-PAK, and D2PAK
  - Type-B: TO-247-4LType-C: D2PAK-7L



Type-A



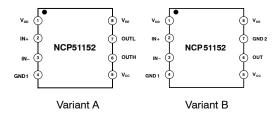
Type-B



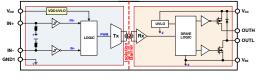
Type-C

Figure 1. Evaluation Board Picture

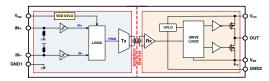
# **PIN CONNECTIONS**



### **FUNCTIONAL BLOCK DIAGRAM**



(a) Separated Output (Variant A)



(b) V<sub>CC</sub> UVLO Referenced to GND2 and external negative bias (Variant B)

### **EVALUATION BOARD OPERATION**

This section describes how to operate the NCP51152 family evaluation board (EVB). Make external connections to the NCP51152 EVB using either the installed test–points or by installing wires into the connectors. The main connections that must be made to the EVB are the analog supply voltage, input signal, and output load and monitoring equipment.

### **Features**

- Evaluation board for the NCP51152 product family in the narrow body (4 mm) SOIC-8 package.
- 3 V to 20 V Input Supply Voltage
- Output Supply Voltage from 6.5 V to 30 V with 6 V and 8 V for MOSFET, 12 V and 17 V for SiC, Threshold.
- 4.5 A and 9 A source/sink current driving capability
- TTL-compatible inputs and allowable input voltage up to V<sub>DD</sub> with for IN+, and IN- pins
- 3-position header with for IN+, and IN- pins
- Support to test with MOSFETs, and SiC MOSFETs with connection to external power stage

## **Power and Ground**

NOTE: Connecting the all power supplies in reverse polarity (backwards) will instantly device when power is turned on and device damage can result.

The primary side of the EVB (V<sub>DD</sub>) operates from a single 3 V to 20 V power supply and connected via J6. Test point (TP9) is available for monitoring the primary power supply. The EVB provides connections for evaluating the output

side ( $V_{CC}$ ,  $V_{EE}$ ) with bipolar power supply from a minimum 6.5 V to maximum 30 V with respect to  $V_{EE}$  pin.

 $V_{\rm CC}$  and  $V_{\rm EE}$  can be monitored with respect to GND2 (TP10) via TP6 and TP11, respectively.

The  $V_{CC}$  pin should be bypassed with a capacitor with a value of at least ten times the gate capacitance of the power device, and over 100 nF and located as close to the device as possible for the purpose of decoupling. A low ESR, ceramic surface mount capacitor is necessary. We had recommends using at least 2 capacitors; an over 100 nF ceramic surface—mount capacitor, and another a tantalum or electrolytic capacitor of few microfarads added in parallel (e.g. C6, C7, C9 and C10).

# **Input and Output**

- 1. Connection of primary–side power supply to the V<sub>DD</sub> and GND1 pins connector [J6–1, and J6–2].
- 2. Connection of secondary–side power supply to the V<sub>CC</sub> and GND2 pins connector [J4–1, and J4–2].
- 3. Connection of secondary–side power supply to the V<sub>EE</sub> and GND2 pins connector [J4–3, and J4–2].
- 4. Connection of non-inverting input signal (IN+) to the SIGNAL connector [J2-1, or J1].
- 5. Connection of inverting input signal (IN-) to the SIGNAL connector [J2-2, or J3].

### **Configuration of Evaluation Board**

The NCP51152 have different output stages of the variant A and B. Therefore, EVBs configuration setting is required to select variant A or B as shown in Table 1.

- Separated Outputs (OUTH, and OUTL) for Variant A
- Wide Bias Voltage Range including Negative V<sub>EE</sub> and V<sub>CC</sub> for Variant B

Table 1. EVB CONFIGURATION SETTING FOR VARIANT A AND B

Туре	PIN7	R3	R5	R7	R8	C8
NCP51152xA	OUTL	3.3 Ω	DNP	DNP	0 Ω	DNP
NCP51152xB	GND2	DNP	3.3 Ω	0 Ω	DNP	470 nF

### **Evaluation Board Jumper Setting**

**Table 2. EVB JUMPER SETTING** 

Jumper	Jumper Setting Options for Input Signals (IN+ & IN-)			
	Option1	Jumper not installed, IN+ signal provided by external signal and this pin is default LOW if left open		
J9-IN+ (INP)	Option2	Jumper on J9-INP-2 and J9-INP-3 set IN+ for LOW state	Option1	
Option		Jumper on J9–INP-2 and J9–INP-1 set IN+ for HIGH state		
	Option1	Jumper not installed, IN- signal provided by external signal and this pin is default HIGH if left open		
J8-IN- (INN) Option2		Jumper on J8-INN-2 and J8-INN-3 set IN- low for LOW state	Option2	
()	Option3	Jumper on J8-INN-2 and J8-INN-1 set IN- high for HIGH state		

## **Evaluation Board Setting before Power Up**

- 1. If the ENABLE mode is used, IN-pin (PIN3) should be connected to GND1(PIN4) through a wire-bridge between pin 2 and pin 3 of J8.
- If using the DISABLE mode, should be connect IN- pin (PIN3) to V<sub>DD</sub> pin (PIN1) through a wire-bridge between pin 1 and pin 2 of J8 or this pin is default HIGH if left open.

### **Bench Setup**

The bench setup diagram includes the function generator, power supplies and oscilloscope connections.

Follow the connection procedure below and use Figure 2 as a reference.

 Make sure all the output of the function generator, power supplies are disabled before connection.

- Function generator channel-B channel (CH2) applied on IN+ (J1 or J2 pin-1) 

  → TP1 as seen in Figure 2.
- Power supply #1: positive node applied on J6 pin-1 (TP9), and negative node applied on J6 pin-2 (TP8).
- Power supply #2: positive node applied on J4 pin-1 (TP6), and negative node connected directly to J4 pin-3 (TP11) with respect to GND2 pin (J4-2 & TP10).
- Oscilloscope channel-A probes TP1 (IN+) ↔ TP8 (GND1), smaller measurement loop is preferred
- Oscilloscope channel−B probes TP2 (IN−) ↔ TP8 (GND1), smaller measurement loop is preferred.
- Oscilloscope channel−C probes TP7 (GATE) ↔ TP10 (GND2), smaller measurement loop is preferred.

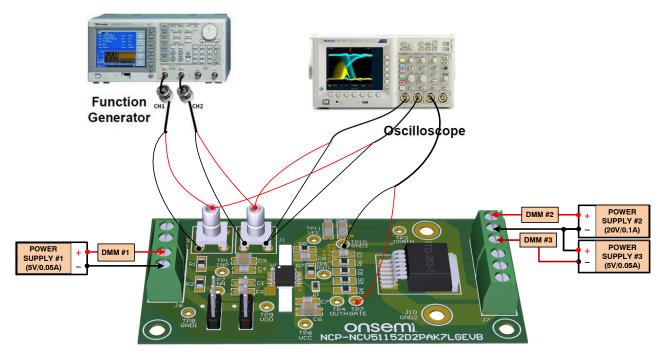


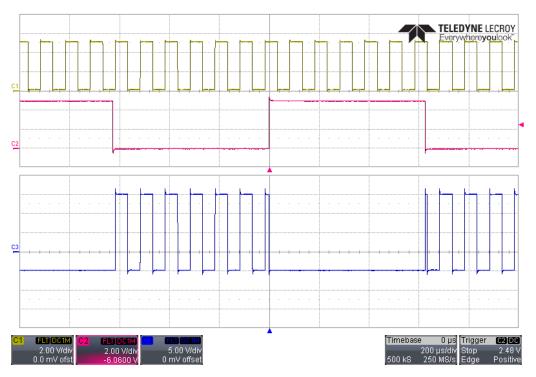
Figure 2. Bench Setup Diagram and Configuration

## Power-Up and Power Down Procedure

Power  $(V_{DD}, V_{CC} \& V_{EE})$  Up Procedure

- 1. Enable power supply through pin1 of J6  $V_{DD}$  connector in primary-side
- 2. Enable power supply through pin1 of J4  $V_{CC}$  connector in secondary–side Measure the quiescent current of  $V_{CC}$  on DMM2 ranges from 0.5 mA to approximately 1.0 mA if everything is set correctly;
- 3. Measure the current of  $V_{EE}$  with respect to GND2 pin on DMM3 if everything is set correctly;

- 4. Enable the function generator, two-channel outputs: channel-A for IN- and channel-B for IN+;
- 5. There will be:
  - a. Stable pulse output on the channel-A, channel-B, and channel-C in the oscilloscope
  - b. Scope frequency measurement is the same with function generator output;
  - c. DMM #2 read measurement results should be around 3 mA ± 1 mA under no load conditions.



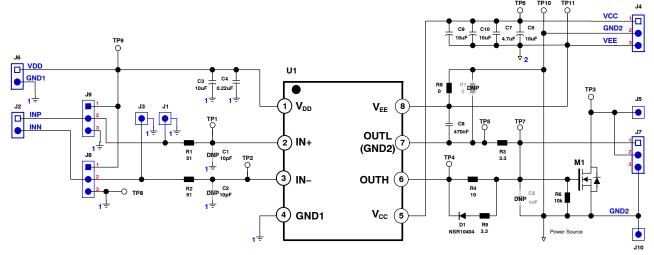
CH1: IN+, CH2: IN-, and CH3: OUT\_GND2

Figure 3. Experimental Waveforms of Input to Output

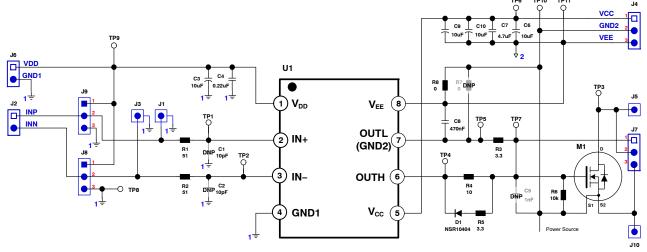
Power (V<sub>DD</sub>, V<sub>CC</sub> & V<sub>EE</sub>) Down Procedure

- 1. Disable function generator
- 2. Disable power supply of  $V_{CC}$  and  $V_{EE}$  in secondary–side
- 3. Disable power supply of V<sub>DD</sub> in primary-side
- 4. Disconnect cables and probes

Figure 4 shows the NCP51152 application schematic of each evaluation board to cope with various package types.



(A) Schematic of Type-A for TO-3P, TO-247, and TO-252 (D-PAK), and TO-263 (D2PAK) Package



(B) Schematic of Type-B for TO-247-4L Package

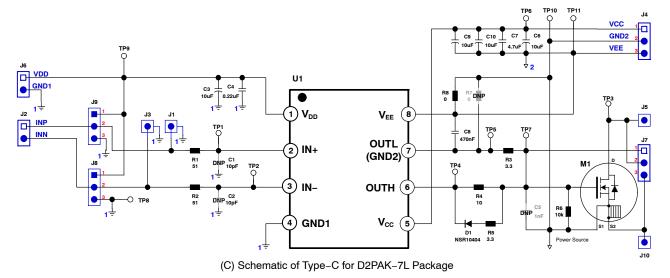


Figure 4. Typical Application Schematic of NCP51152

# **List of Test Point**

Table 3 shows the test point list of NCP51152 for an evaluation board (EVB).

# **Table 3. LIST OF TEST POINT**

TP	Reference	Description
TP1	INP	Non-inverting Logic Input with internal pull-down resistor to GND1
TP2	INN	Inverting Logic Input with internal pull-up resistor to V <sub>DD</sub>
TP3	DRAIN	Drain of switch
TP4	OUTH	Gate Drive Pull-up Output (Source Output)
TP5	OUTL	Gate Drive Pull-down Output (Sink Output)
TP6	VCC	Positive Output Supply Rail
TP7	GATE	Gate of switch
TP8	GND1	Ground Input-side. (all signals on input-side are referenced to this pin)
TP9	VDD	Input-side Supply Voltage. It is recommended to place a bypass capacitor from V <sub>DD</sub> to GND1.
TP10	GND2	Gate-drive common pin. Connect this pin to the MOSFET source. V <sub>CC</sub> UVLO threshold referenced to GND2.
TP11	VEE	Negative output supply rail

# **Electrical Specifications**

Table 4 shows the recommended operating conditions of NCP51152 for an evaluation board.

**Table 4. ELECTRICAL SPECIFICATIONS** 

Rating	Symbol	Min.	Max.	Unit	
Power Supply Voltage – Input side		V <sub>DD</sub>	3.0	20	V
Power Supply Voltage – Driver side	6-V UVLO Version	V <sub>CC</sub>	6.5	30	V
	8-V UVLO Version	]	9.5	30	V
	12-V UVLO Version	1	13.5	30	V
	17-V UVLO Version	1	18.5	30	V
Negative Supply Voltage for only Variant B (NCP51152xB)		VEE – GND2	-15	0	V
Logic Input Voltage at pins IN+, and IN-		V <sub>IN</sub>	0	$V_{DD}$	V
Ambient Temperature		T <sub>A</sub>	-40	+125	°C
Junction Temperature		TJ	-40	+125	°C
Common Mode Transient Immunity		CMTI	200		kV/μs

### **Bill of Material (BOM)**

Table 5 shows the bill of material (BOM) of NCP51152 for an evaluation board.

**Table 5. BILL OF MATERIAL** 

Reference	Qty	Description	Value	Footprint	Manufacturer
U1	1	Gate driver	NCP51152	8-SOIC-NB	onsemi
D1	1	Diode	US1MFA	SMB/DO214AA	onsemi
R1,R2	2	Resistor	51 Ω	SMD 0805W	Rohm
R3 ,R5	2	Resistor	3.3 Ω	SMD 0805W	Rohm
R4	1	Resistor	10 Ω	SMD 0805W	Rohm
R6	1	Resistor	10 kΩ	SMD 0805W	Rohm
C1, C2	2	Capacitor, Ceramic	10 pF, 50 V	SMD 0805W	Yageo
C3, C6, C9, C10	4	Capacitor, Ceramic	10 uF, 50 V	SMD 3216	Yageo
C4	1	Capacitor, Ceramic	0.22 uF, 50 V	SMD 3216	Yageo
C7	1	Capacitor, Ceramic	4.7 uF, 50 V	SMD 0805W	Yageo
C8	1	Capacitor, Ceramic	For only NCP51152xB	SMD 0805W	Yageo
C5	1	Capacitor, Ceramic	1 nF (DNP), 50 V	SMD 0805W	Yageo
M1	0	Switch	For Only Type-A	TO-247-3L	onsemi
			For Only Type-B	TO-247-4L	onsemi
			For Only Type-C	D2PAK-7L	onsemi
J1, J3	2	BNC Connector		SMB	Johnson / Cinch
J2,J6	2	Connector	2 Pin		CAMDEN
J4,J7	2	Connector	3 Pin		CAMDEN
J8, J9	2	Header	3 Pin	Pltch 2.54mm	JINLING
J5, J10	0	Connector	DNP		

**EVBs Configuration Setting for Variant A or B** 

R7	<b>DNP</b> for NCP51152xA, and <b>0</b> $\Omega$ for NCP51152xB
R8	${f 0}~\Omega$ for NCP51152xA, and ${f DNP}$ for NCP51152xB

# **Input Stage**

The input pins of NCP51152 is based on a TTL-compatible input—threshold logic that is independent of the  $V_{DD}$  supply voltage for IN+, and IN- pins. The logic level compatible input provides a typically HIGH and LOW threshold of 1.63 V and 1.08 V respectively. The input signal pins impedance is 125 k $\Omega$  typically and the IN+ pin is pulled to GND1 pin and IN- pin is pulled to  $V_{DD}$  pin as shown in Figure 5. For non-inverting input logic signal is applied to IN+ while the IN- input can be used as an enable function. If IN- is pulled HIGH, the driver output remains LOW state, regardless of the state of IN+. To enable the driver output, IN- should be tied to GND1 pin through a few ten k $\Omega$  resistor (e.g.10 k $\Omega$ ) or can be used as an active LOW enable pull down.

- Non-inverting input IN+ controls the driver output while inverting input IN- is set to LOW
- Inverting input IN– controls the driver output while non–inverting input IN+ is set to HIGH.

And we recommend an RC network is to be added on the PWM input pins, IN+ and IN-, for reducing the impact of system noise and ground bounce, for example, 51  $\Omega$  (R1, and R2) with 10 pF (C1, and C2) is an acceptable choice as shown in Figure 5. IN+, and IN- signal can be monitored via TP1, and TP2, respectively.

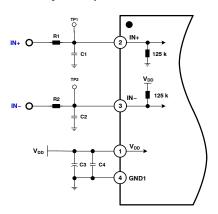


Figure 5. Recommended Input Circuit

### **Output Stage**

The output stage is able to sink/source typically around +4.5 A/-9.0 A at 25°C for the NCP51152.

The NCP51152 have different output stages of the variant A and B as shown in Figure 6.

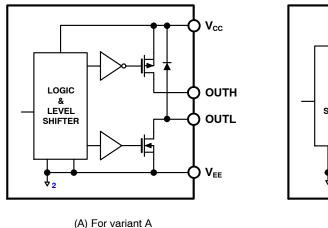
For the variant A is designed to support separate source (OUTH) and sink (OUTL) outputs. This scheme allows a single resistor between each pin and the MOSFET gate to independently control gate ringing as well as fine tuning  $dV_{DS}/dT$  turn–on and turn–off transitions present on the MOSFET drain–source voltage.

The EVB comes populated with a 1 nF load (C5) on the output side. The OUTH, OUTL and GATE can be monitored directly via TP4, TP5 and TP7, respectively.

The Type–A EVB allows for evaluation of the device with an MOSFET load in either of the standard TO–3P, TO–247–3L, and TO–252 (D–PAK), and TO–263 (D2PAK) footprints. The Type–B EVB allows for evaluation of the device with an MOSFET load in the standard TO–247–4L The Type–C EVB allows for evaluation of the device with an MOSFET load in the standard D2PAK–7L.

During evaluation with an SiC MOSFET load, the pre–installed capacitive load (C5) can be disconnected from the output. The EVB provides an additional connection (J5) for applying an external power supply to the MOSFET Drain. The EVB is not intended for high voltage testing and the voltage applied to J5 should be limited to  $50\,V_{DC}$ .

 $V_{cc}$ 



LOGIC & OUT SHIFTER VEE GND2

(B) For variant B

Figure 6. Schematic of Output Stage

### **Functional Mode Table**

Table 6 and Table 7 show the functional modes for the NCP51152 variant A and B assuming VDD and VCC are in the recommended ranges for an evaluation board.

**Table 6. FUNCTIONAL MODES FOR VARIANT A** 

INP	TUT	GATE DRIVE OUTPUT		
IN+	IN-	OUTH	OUTL	
LOW	Х	Hi–Z	LOW	
Х	HIGH	Hi–Z	LOW	
HIGH	LOW	HIGH	Hi–Z	

**Table 7. FUNCTIONAL MODES FOR VARIANT B** 

INPUT		GATE DRIVE OUTPUT	
IN+	IN-	OUT	
LOW	Х	Low	
Х	HIGH	Low	
HIGH	LOW	High	

## PERFORMANCE OF EVALUATION BOARD

This section describes application guidance and operation of the NCP51152 for an evaluation board (EVB) include key functions.

### **Protection Function**

The NCP51152 provides important protection functions such as independent under-voltage lockout for gate driver. Figure 7 shows an overall input to output timing diagram.

Under–Voltage Lockout protection on the primary– and secondary–sides power supplies events in the **CASE–A, B** and **C** and the gate driver output (OUT) is immediately turn–off when an inverting input signal (IN–) is HIGH regardless non–inverting input (IN+) signal state in the **CASE–D**. The negative bias control circuit is enabled after the  $V_{CC}$  power–up delay time,  $t_{VPOR\ to\ OUT}$ , during initial  $V_{CC}$  start–up or after POR event.

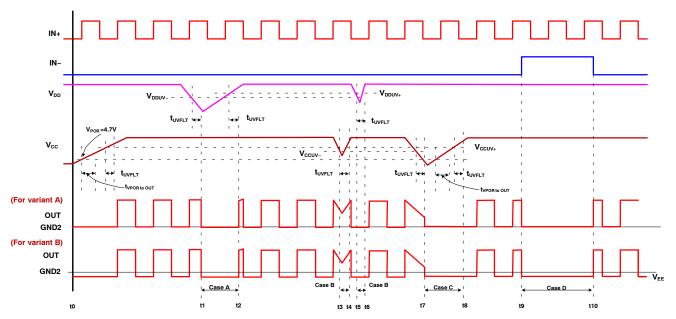
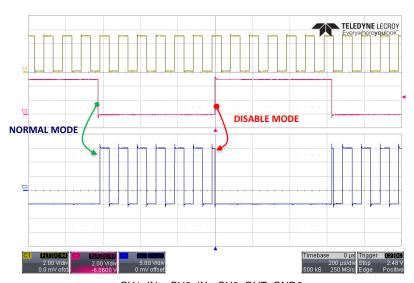


Figure 7. Overall Operating Waveforms Definitions

Figure 8 shows an experimental result of enable function that the inverting input pin (IN-) voltage goes to HIGH state in normal operation, the gate driver output is turned-off

immediately regardless non-inverting input (IN+) pin signal state.



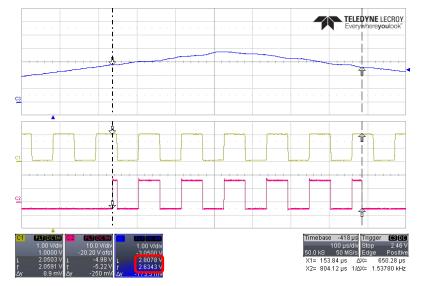
CH1: IN+, CH2: IN-, CH3: OUT\_GND2

Figure 8. Experimental Waveforms of Enable Function

# Under-Voltage Lockout Protection V<sub>DD</sub>

The NCP51152 provides the Under-Voltage Lockout (UVLO) protection function for  $V_{DD}$  in primary-side.

As test result, the  $V_{DD}$  UVLO turn-on and off threshold voltages are around 2.8 V and 2.63 V respectively as shown in Figure 9.



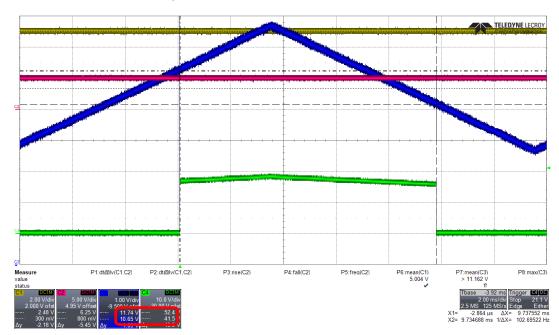
CH1: IN+, CH2: OUT\_VEE, CH3: VDD

Figure 9. Experimental Waveforms of  $V_{DD}$  Under-Voltage Lockout Protection

# Under-Voltage Lockout Protection V<sub>CC</sub>

The NCP51152 provides the Under-Voltage Lockout (UVLO) protection function of gate drive output in secondary-side. As test result of NCP51152CB variant (For example, VCC UVLO Threshold = 12 V), the  $V_{CC}$  UVLO

turn-on and off threshold voltages are around 11.74 V and 10.65 V with respect to GND2 respectively due to GND2\_VEE external bias voltage is 5-V as shown in Figure 10.



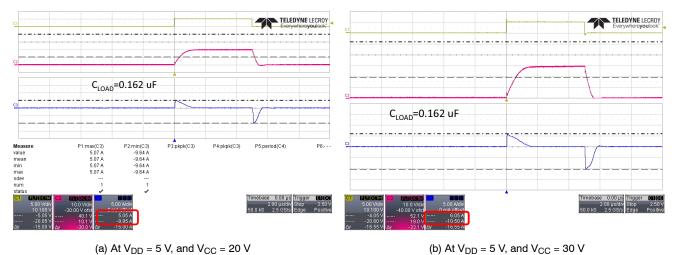
CH1: IN+, CH2: VDD, CH3: VCC\_VEE and CH4: OUT\_VEE

Figure 10. Experimental Waveforms of  $V_{\text{CC}}$  Under-Voltage Lockout Protection

## **Output Driving Current Capability**

The experimental result of source and sink peak currents driving capability around 5.0 A and 9.95 A respectively at  $V_{CC} = 20 \text{ V}$  and room temperature as shown in Figure 11 (a).

And source and sink peak currents driving capability around 6.0 A and 10.5 A respectively at  $V_{CC}$  = 30 V and room temperature as shown in Figure 11 (b).



CH1: IN+, CH2: OUT VEE, CH3: OUT Current

Figure 11. Experimental Waveforms of Current Driving Capability

### **ESD Structure**

Figure 12 shows the multiple diodes related to an ESD protection components of NCP51152 for variants A and B. This illustrates the absolute maximum rating for the device.

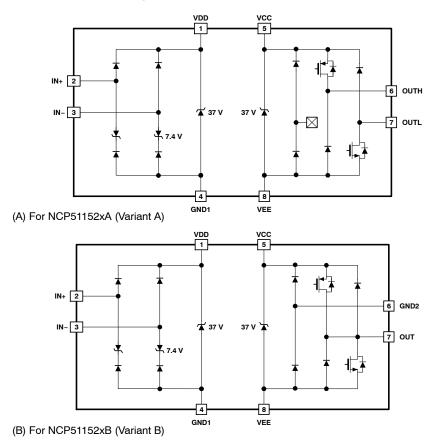


Figure 12. ESD Structure

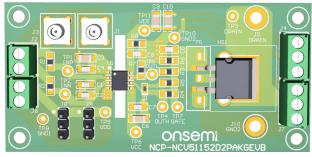
# **Printed Circuit Board**

Figure 13 shows the photograph of the NCP51152 evaluation board for the Type-A. This EVB allows for

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(A) For TO-247-3L Package

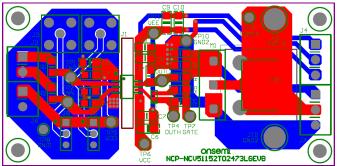
evaluation of the device with an MOSFET load in either of the standard TO-3P, TO-247, TO-252 (D-PAK), and TO-263 (D2PAK) footprints.



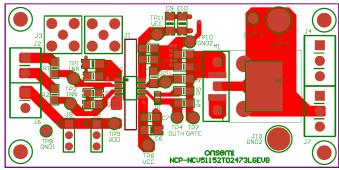
(B) For D2PAK Package

Figure 13. Evaluation Board Picture of Type-A (Top View)

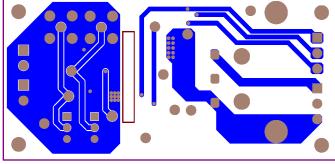
Figure 14 shows the printed circuit board layout of NCP51152 evaluation board for the Type-A.



(A) Top & Bottom View



(B) Top View



(C) Bottom View

Figure 14. Printed Circuit Board of Type-A

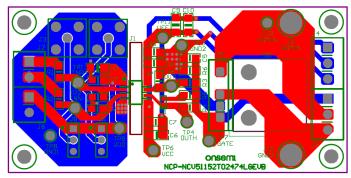
Figure 15 shows the photograph of the NCP51152 evaluation board for the Type-B. This EVB allows for

evaluation of the device with an MOSFET load in the standard TO-247-4L footprint.

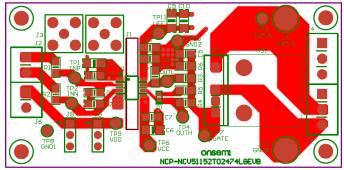


Figure 15. Evaluation Board Picture of Type-B (Top View)

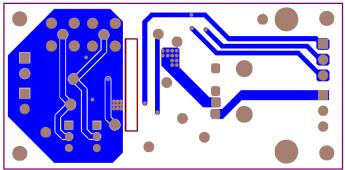
Figure 16 shows the printed circuit board layout of NCP51152 evaluation board for the Type-B.



(A) Top & Bottom View



(B) Top View



(C) Bottom View

Figure 16. Printed Circuit Board of Type-B

Figure 17 shows the photograph of the NCP51152 evaluation board board for the Type-C. This EVB allows for

evaluation of the device with an MOSFET load in the standard D2PAK-7L footprint.

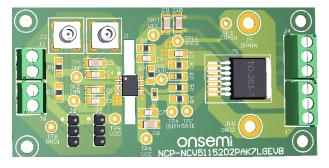
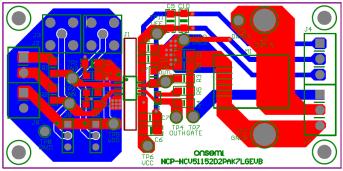
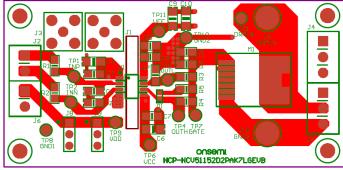


Figure 17. Evaluation Board Picture of Type-C (Top View)

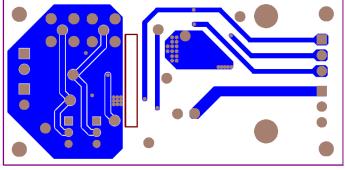
Figure 16 shows the printed circuit board layout of NCP51152 evaluation board for the Type-B.



(A) Top & Bottom View



(B) Top View



(C) Bottom View

Figure 18. Printed Circuit Board of Type-C

# **Related Product Information**

- [1] Datasheet of NCP51152 available on onsemi website
- [2] Datasheet of NCV51152 available on onsemi website
- [3] **onsemi** AND90180/D, "Practical Design Guidelines on the Usage of an Isolated Gate Driver"

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